

Notice of Allowability	Application No.	Applicant(s)	
	10/600,238	KELLERMAN ET AL.	
	Examiner	Art Unit	
	Elias Desta	2857	

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address--

All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. **THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS.** This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.

1. ☒ This communication is responsive to Amendment filed on 11/24/2004.
2. ☒ The allowed claim(s) is/are 11-13.
3. ☒ The drawings filed on 13 June 2003 are accepted by the Examiner.
4. ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
 - a) ☐ All b) ☐ Some* c) ☐ None of the:
 1. ☐ Certified copies of the priority documents have been received.
 2. ☐ Certified copies of the priority documents have been received in Application No. _____.
 3. ☐ Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).

* Certified copies not received: _____.

Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application.

THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.

5. ☐ A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.
6. ☐ CORRECTED DRAWINGS (as "replacement sheets") must be submitted.
 - (a) ☐ including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached
 - 1) ☐ hereto or 2) ☐ to Paper No./Mail Date _____.
 - (b) ☐ including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date _____.

Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d).
7. ☐ DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.

Attachment(s)

- | | |
|---|---|
| <ol style="list-style-type: none"> 1. <input type="checkbox"/> Notice of References Cited (PTO-892) 2. <input type="checkbox"/> Notice of Draftsperson's Patent Drawing Review (PTO-948) 3. <input type="checkbox"/> Information Disclosure Statements (PTO-1449 or PTO/SB/08),
Paper No./Mail Date _____ 4. <input type="checkbox"/> Examiner's Comment Regarding Requirement for Deposit
of Biological Material | <ol style="list-style-type: none"> 5. <input type="checkbox"/> Notice of Informal Patent Application (PTO-152) 6. <input type="checkbox"/> Interview Summary (PTO-413),
Paper No./Mail Date _____ 7. <input checked="" type="checkbox"/> Examiner's Amendment/Comment 8. <input checked="" type="checkbox"/> Examiner's Statement of Reasons for Allowance 9. <input type="checkbox"/> Other _____ |
|---|---|

Detailed Action

Title/Specification

1. The Examiner accepts the new title and the amendment to the specification.

Allowance

2. Claims 1-10 are canceled. The amended claim 11 and the newly added claims 12 and 13 are allowed. The following is an examiner's statement of reasons for allowance:

In reference to claims 11, 12 and 13: *Swoboda et al.* (U.S. Patent 6,704,895) teaches an IC tester (see *Swoboda et al.*, Fig. 23 and column 3, lines 16-20). The tester includes:

- A test head fixture (see *Swoboda et al.*, Fig. 23, member 1651, wafer head) for electrically interconnecting (member 1665) with an IC DUT (wafer 1657) to apply test signals for test program having at least one scan test and to acquire results data from execution of the test program (see *Swoboda et al.*, column 33, lines 30-65);
- A controller for causing the test head fixture to execute the test program on the IC DUT (see *Swoboda et al.*, Fig. 23, Wafer Test Head Scans in or out data through the Controller Card to the Testing Environment);

- A data Storage (see *Swoboda et al.*, Fig. 23, member 1145) having test program specification (where the system has a test program and a storage which necessarily indicates that the program resides in a storage unit such as a hard drive as shown in Fig. 23, and Fig. 31), a compiled program such as the C program (see *Swoboda et al.*, column 5, lines 33-52) and the cross reference data (see *Swoboda et al.*, column 5, lines 60-64). The archive (the data store) allows collection of group of files into a single archive which has a function of interrelating the test program specification (macros), compiled test program (EPROM programmer format) and test execution results data (executed on a target chip) (see *Swoboda et al.*, column 6, lines 13-41); and
- A scan-test viewing tool (see *Swoboda et al.*, Fig. 24, Testing Environment Monitor) for presenting a set of views relating to the scan test on a display for viewing by the user, the views includes a cyclic view of an execution of test program that is necessary present because simulation executing code includes single/multiple cycle counts (see *Swoboda et al.*, column 6, lines 27-41). Further the scan test-viewing tool includes the procedural view of the test program (see *Swoboda et al.*, Fig. 15), and resulting scan vector (initial state or test vector) (see *Swoboda et al.*, column 18, lines 35-42). The scan test viewing tool provides navigational links for navigating between a location in one of

the views to a correlated location in another of the views is necessarily present because the system in Swoboda et al. Fig. 2 shows that the system has an emulation feature to emulate the wafer scale chips, or IC as shown in Fig. 23.

Swoboda et al. does not teach having modifying the test program definition in response to user editing inputs. The claimed invention further includes acquiring test execution results from execution of the modified test program and repeating the above noted processing, rendering, presenting and navigating steps based on modified test program for analyzing the modified test of the IC device.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

3. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Elias Desta whose telephone number is (571)-272-2214. The examiner can normally be reached on M-Thu (8:30-7:00).

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Marc S. Hoff can be reached on (571)-272-2216. The fax phone numbers for the organization where this application or proceeding is

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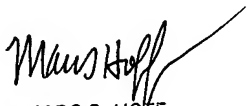
assigned are (703)-872-9306 for regular communications and After Final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is (571)-272-1750.

Elias Desta
Examiner
Art Unit 2857

-ed

February 28, 2005


MARC S. HOFF
SUPERVISORY PATENT EXAMINER
TECHNOLOGY CENTER 2800